

<b>Notice of References Cited</b>	Application/Control No. 10/572,932	Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
	Examiner Sean E. Aeder, Ph.D.	Art Unit 1642	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0092009	05-2003	Palm, Kaia	435/6
	B	US-			
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**FOREIGN PATENT DOCUMENTS**

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